



# EMI TEST REPORT


**Test Report No. : 13584430H-B-R1**

**Applicant** : Mitsubishi Electric Corporation Himeji works  
**Type of EUT** : Smart Keyless System (Smart Unit)  
**Model Number of EUT** : SKE45A-03  
**FCC ID** : WAZSKE45A03  
**Test regulation** : FCC Part 15 Subpart B: 2020  
**Test Result** : Complied (Refer to SECTION 3.2)


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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the limits of the above regulation.
4. The test results in this test report are traceable to the national or international standards.
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6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)
7. The all test items in this test report are conducted by UL Japan, Inc. Ise EMC Lab.
8. The opinions and the interpretations to the result of the description in this report are outside scopes where UL Japan has been accredited.
9. The information provided from the customer for this report is identified in SECTION 1.
10. This report is a revised version of 13584430H-B. 13584430H-B is replaced with this report.

**Date of test:** November 27, 2020

**Representative test engineer:**

  
Akihiko Maeda  
Engineer  
Consumer Technology Division

**Approved by:**

  
Motoya Imura  
Leader  
Consumer Technology Division



CERTIFICATE 5107.02

- ☐ The testing in which "Non-accreditation" is displayed is outside the accreditation scopes in UL Japan.  
☒ There is no testing item of "Non-accreditation".

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## **REVISION HISTORY**

### **Original Test Report No.: 13584430H-B**

Revision	Test report No.	Date	Page revised	Contents
- (Original)	13584430H-B	December 22, 2020	-	-
1	13584430H-B-R1	December 25, 2020	P.5	Addition of the Voltage Controlled Oscillator in RF Part of Clause 2.2.
1	13584430H-B-R1	December 25, 2020	P.6	Correction of the Symbols of Result in Procedure of Clause 3.2; From “Complied#” to “Complied”
1	13584430H-B-R1	December 25, 2020	P.12	Addition of 314.720 MHz in Below 1 GHz data

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## Reference: Abbreviations (Including words undescribed in this report)

AAN	Asymmetric Artificial Network	ILAC	International Laboratory Accreditation Conference
AC	Alternating Current	ISED	Innovation, Science and Economic Development Canada
AM	Amplitude Modulation	ISN	Impedance Stabilization Network
AMN	Artificial Mains Network	ISO	International Organization for Standardization
Amp, AMP	Amplifier	JAB	Japan Accreditation Board
ANSI	American National Standards Institute	LAN	Local Area Network
Ant, ANT	Antenna	LCL	Longitudinal Conversion Loss
AP	Access Point	LIMS	Laboratory Information Management System
ASK	Amplitude Shift Keying	LISN	Line Impedance Stabilization Network
Atten., ATT	Attenuator	MRA	Mutual Recognition Arrangement
AV	Average	N/A	Not Applicable
BPSK	Binary Phase-Shift Keying	NIST	National Institute of Standards and Technology
BR	Bluetooth Basic Rate	NS	No signal detect.
BT	Bluetooth	NSA	Normalized Site Attenuation
BT LE	Bluetooth Low Energy	NVLAP	National Voluntary Laboratory Accreditation Program
BW	BandWidth	OBW	Occupied Band Width
C.F	Correction Factor	OFDM	Orthogonal Frequency Division Multiplexing
Cal Int	Calibration Interval	PK	Peak
CAV	CISPR AV	PLT	long-term flicker severity
CCK	Complementary Code Keying	POHC(A)	Partial Odd Harmonic Current
CDN	Coupling Decoupling Network	Pol., Pola.	Polarization
Ch., CH	Channel	PR-ASK	Phase Reversal ASK
CISPR	Comite International Special des Perturbations Radioelectriques	PST	short-term flicker severity
Corr.	Correction	QAM	Quadrature Amplitude Modulation
CPE	Customer premise equipment	QP	Quasi-Peak
CW	Continuous Wave	QPSK	Quadri-Phase Shift Keying
DBPSK	Differential BPSK	r.m.s., RMS	Root Mean Square
DC	Direct Current	RBW	Resolution Band Width
DET	Detector	RE	Radio Equipment
D-factor	Distance factor	REV	Reverse
Dmax	maximum absolute voltage change during an observation period	RF	Radio Frequency
DQPSK	Differential QPSK	RFID	Radio Frequency Identifier
DSSS	Direct Sequence Spread Spectrum	RSS	Radio Standards Specifications
EDR	Enhanced Data Rate	Rx	Receiving
e.i.r.p., EIRP	Equivalent Isotropically Radiated Power	SINAD	Ratio of (Signal + Noise + Distortion) to (Noise + Distortion)
EM clamp	Electromagnetic clamp	S/N	Signal to Noise ratio
EMC	ElectroMagnetic Compatibility	SA, S/A	Spectrum Analyzer
EMI	ElectroMagnetic Interference	SG	Signal Generator
EMS	ElectroMagnetic Susceptibility	SVSWR	Site-Voltage Standing Wave Ratio
EN	European Norm	THC(A)	Total Harmonic Current
e.r.p., ERP	Effective Radiated Power	THD(%)	Total Harmonic Distortion
EU	European Union	TR	Test Receiver
EUT	Equipment Under Test	Tx	Transmitting
Fac.	Factor	VBW	Video BandWidth
FCC	Federal Communications Commission	Vert.	Vertical
FHSS	Frequency Hopping Spread Spectrum	WLAN	Wireless LAN
FM	Frequency Modulation	xDSL	Generic term for all types of DSL technology (DSL: Digital Subscriber Line)
Freq.	Frequency		
FSK	Frequency Shift Keying		
Fund	Fundamental		
FWD	Forward		
GFSK	Gaussian Frequency-Shift Keying		
GNSS	Global Navigation Satellite System		
GPS	Global Positioning System		
Hori.	Horizontal		
ICES	Interference-Causing Equipment Standard		
I/O	Input/Output		
IEC	International Electrotechnical Commission		
IEEE	Institute of Electrical and Electronics Engineers		
IF	Intermediate Frequency		

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## **SECTION 1: Customer information**

Company Name	:	Mitsubishi Electric Corporation Himeji works
Address	:	840 Chiyoda-machi, Himeji, Hyogo 670-8677, Japan
Telephone Number	:	+81-79-298-7363
Facsimile Number	:	+81-79-298-9929
Contact Person	:	Yasuhiro Takahashi

The information provided from the customer is as follows;

- Applicant, Type of EUT, Model Number of EUT, FCC ID on the cover and other relevant pages
- Operating/Test Mode(s) (Mode(s)) on all the relevant pages
- SECTION 1: Customer information
- SECTION 2: Equipment under test (EUT) other than the Receipt Date
- SECTION 4: Operation of EUT during testing

\* The laboratory is exempted from liability of any test results affected from the above information in SECTION 2 and 4.

## **SECTION 2: Equipment under test (EUT)**

### **2.1 Identification of EUT**

Type	:	Smart Keyless System (Smart Unit)
Model Number	:	SKE45A-03
Serial Number	:	Refer to SECTION 4.2
Rating	:	DC 12.0 V
Receipt Date	:	November 11, 2020
Country of Mass-production	:	Japan
Condition	:	Production prototype (Not for Sale: This sample is equivalent to mass-produced items.)
Modification	:	No Modification by the test lab

### **2.2 Product Description**

Model: SKE45A-03 (referred to as the EUT in this report) is a Smart Keyless System (Smart Unit).

### **Radio Specification**

#### **LF Part \***

Equipment Type	:	Transmitter
Frequency of operation	:	125 kHz
Type of modulation	:	ASK
Other clock frequency	:	-
Antenna Type	:	Inductive
Clock frequency (maximum)	:	8 MHz

#### **RF Part**

Type of Receiver	:	Receiver
Frequency of operation	:	315 MHz
Other clock frequency	:	30.32 MHz
Intermediate frequency	:	280 kHz
Antenna Type	:	Bar Antenna
Voltage Controlled Oscillator	:	1888.32 MHz

\* EUT also has this function. Please refer to No. 13584430H-A (FCC15C).

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## **SECTION 3: Test specification, procedures & results**

### **3.1 Test Specification**

Test Specification : FCC Part 15 Subpart B  
 FCC Part 15 final revised on October 13, 2020  
 Title : FCC 47CFR Part15 Radio Frequency Device  
 Subpart B Unintentional Radiators

### **3.2 Procedures and results**

Item	Test Procedure	Limits	Deviation	Worst margin	Result	Remarks
Conducted emission	<b>FCC:</b> ANSI C63.4: 2014 + C63.4a: 2017 7. AC power - line conducted emission measurements	<b>FCC:</b> Part 15 Subpart B 15.107(a)	N/A	N/A	N/A	*1)
	<b>ISED:</b> RSS-Gen 7.1	<b>ISED:</b> RSS-Gen 7.2				
Radiated emission	<b>FCC:</b> ANSI C63.4: 2014 + C63.4a: 2017 8. Radiated emission measurements	<b>FCC:</b> Part 15 Subpart B 15.109(a)	N/A	22.9 dB 945.840 MHz, Horizontal, QP	Complied a)	-
	<b>ISED:</b> RSS-Gen 7.1	<b>ISED:</b> RSS-Gen 7.3				
Antenna Terminal	<b>FCC:</b> ANSI C63.4: 2014 + C63.4a: 2017 12. Measurement of unintentional radiators other than ITE	<b>FCC:</b> Part 15 Subpart B 15.111(a)	N/A	N/A	N/A	*2)
	<b>ISED:</b> - RSS-Gen 7.1	<b>ISED:</b> RSS-Gen 7.4				
*Note: UL Japan, Inc’s EMI Work Procedure 13-EM-W0420.						
*1) The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.						
*2) The receiving antenna (of this EUT) is installed inside the EUT and cannot be removed (permanently attached). Therefore, Radiated emission test was performed.						
a) Refer to APPENDIX 1 (data of Radiated Emission)						
Symbols:						
Complied		The data of this test item has enough margin, more than the measurement uncertainty.				
Complied#		The data of this test item meets the limits unless the measurement uncertainty is taken into consideration.				

### **3.3 Addition to standard**

No addition, exclusion nor deviation has been made from the standard.

### 3.4 Uncertainty

There is no applicable rule of uncertainty in this applied standard. Therefore, the results are derived depending on whether or not laboratory uncertainty is applied.

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor  $k = 2$ .

#### Radiated emission

Measurement distance	Frequency range		Uncertainty (+/-)
3 m	30 MHz to 200 MHz	(Horizontal)	4.8 dB
		(Vertical)	5.0 dB
	200 MHz to 1000 MHz	(Horizontal)	5.2 dB
		(Vertical)	6.3 dB
10 m	30 MHz to 200 MHz	(Horizontal)	4.8 dB
		(Vertical)	4.8 dB
	200 MHz to 1000 MHz	(Horizontal)	5.0 dB
		(Vertical)	5.0 dB
3 m	1 GHz to 6 GHz		4.9 dB
	6 GHz to 18 GHz		5.2 dB
1 m	10 GHz to 26.5 GHz		5.5 dB
	26.5 GHz to 40 GHz		5.5 dB
0.5 m	26.5 GHz to 40 GHz		5.5 dB
10 m	1 GHz to 18 GHz		5.2 dB

### 3.5 Test Location

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\* A2LA Certificate Number: 5107.02/ FCC Test Firm Registration Number: 199967 / ISED Lab Company Number: 2973C

Test site	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms	Maximum measurement distance
No.1 semi-anechoic chamber	19.2 x 11.2 x 7.7	7.0 x 6.0	No.1 Power source room	10 m
No.2 semi-anechoic chamber	7.5 x 5.8 x 5.2	4.0 x 4.0	-	3 m
No.3 semi-anechoic chamber	12.0 x 8.5 x 5.9	6.8 x 5.75	No.3 Preparation room	3 m
No.3 shielded room	4.0 x 6.0 x 2.7	N/A	-	-
No.4 semi-anechoic chamber	12.0 x 8.5 x 5.9	6.8 x 5.75	No.4 Preparation room	3 m
No.4 shielded room	4.0 x 6.0 x 2.7	N/A	-	-
No.5 semi-anechoic chamber	6.0 x 6.0 x 3.9	6.0 x 6.0	-	-
No.5 measurement room	6.4 x 6.4 x 3.0	6.4 x 6.4	-	-
No.6 shielded room	4.0 x 4.5 x 2.7	4.0 x 4.5	-	-
No.6 measurement room	4.75 x 5.4 x 3.0	4.75 x 4.15	-	-
No.7 shielded room	4.7 x 7.5 x 2.7	4.7 x 7.5	-	-
No.8 measurement room	3.1 x 5.0 x 2.7	3.1 x 5.0	-	-
No.9 measurement room	8.8 x 4.6 x 2.8	2.4 x 2.4	-	-
No.11 measurement room	6.2 x 4.7 x 3.0	4.8 x 4.6	-	-

\* Size of vertical conducting plane (for Conducted Emission test) : 2.0 m x 2.0 m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

### 3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

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## **SECTION 4: Operation of EUT during testing**

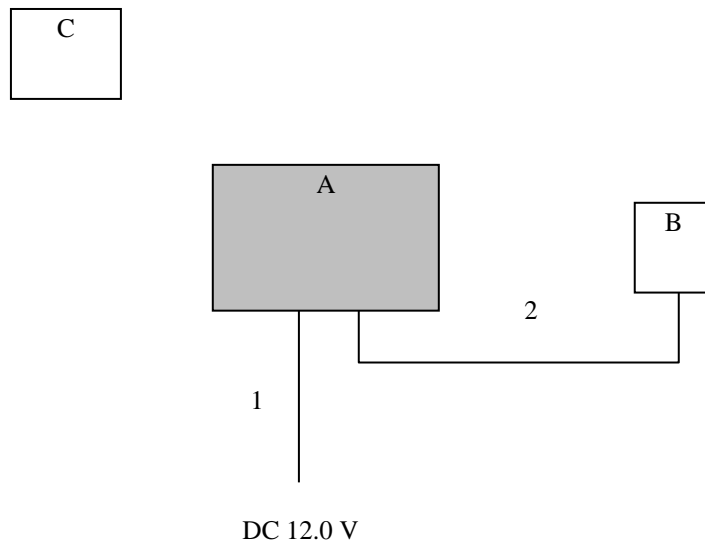
### **4.1 Operating Mode(s)**

Mode	Remarks
Receiving mode	-
* EUT was set by the software as follows; Software: J979 Version 001	

\*The test signal level was confirmed to be sufficient to stabilize the local oscillator of the EUT.

\* It was confirmed by using LED that the EUT receives the signal from the transmitter (pair of EUT).

### **4.2 Configuration and peripherals**



\* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

#### **Description of EUT and Support equipment**

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Smart Keyless System Smart Unit	SKE45A-03	20201103-E9	Mitsubishi Electric Corporation Himeji works	EUT
B	LED	-	-	-	-
C	Smart Keyless System Hand Unit	SKE45A-02	20201103-T3	Mitsubishi Electric Corporation Himeji works	-

#### **List of cables used**

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	1.7	Unshielded	Unshielded	-
2	Signal Cable	2.0	Unshielded	Unshielded	-

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## **SECTION 5: Radiated Emission**

### **5.1 Operating environment**

Test place : No.4 semi anechoic chamber  
Temperature : See data  
Humidity : See data

### **5.2 Test configuration**

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The EUT was set on the center of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

### **5.3 Test conditions**

Frequency range : 30 MHz - 200 MHz (Biconical antenna) / 200 MHz - 1000 MHz (Logperiodic antenna)  
1000 MHz - 10000 MHz (Horn antenna)  
Test distance : 3 m  
EUT position : Table top  
EUT operation mode : See Clause 4.1

### **5.4 Test procedure**

The height of the measuring antenna varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver.

The radiated emission measurements were made with the following detector function of the Test Receiver.

For above 1 GHz, test antenna was aimed at the EUT for receiving the maximum signal and always kept within the illumination area of the 3 dB beamwidth of the antenna.

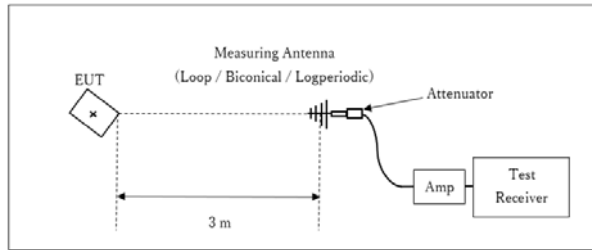
Frequency	Below 1GHz	Above 1GHz *1)
Instrument used	Test Receiver	Test Receiver
IF Bandwidth	QP: BW 120 kHz	PK: BW 1 MHz, CISPR AV: BW 1 MHz

\*1) The measurement data was adjusted to a 3 m distance using the following Distance Factor.

Distance Factor: See Figure 2.

**Figure 2: Test Setup**

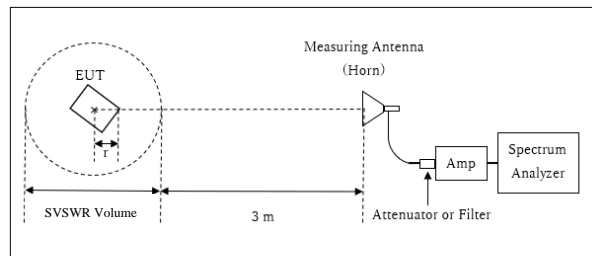
Below 1 GHz



x : Center of turn table

Test Distance: 3 m

1 GHz - 10 GHz



r : Radius of an outer periphery of EUT

x : Center of turn table

Distance Factor:  $20 \times \log (3.9 \text{ m}/3.0 \text{ m}) = 2.28 \text{ dB}$

\* Test Distance:  $(3 + \text{SVSWR Volume} / 2) - r = 3.9 \text{ m}$

SVSWR Volume: 2 m

(SVSWR Volume has been calibrated based on CISPR 16-1-4.)

$r = 0.1 \text{ m}$

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

## 5.5 Test result

Summary of the test results: Pass

The limit is rounded down to one decimal place.

The test result is rounded off to one or two decimal places, so some differences might be observed.

Date: November 27, 2020

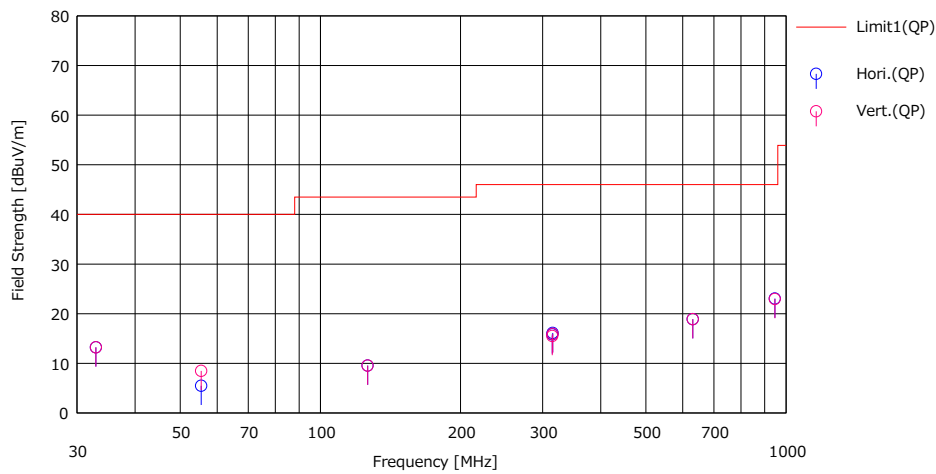
Test engineer: Akihiko Maeda

## APPENDIX 1: Test data

### Radiated Emission

Report No. 13584430H  
Test place Ise EMC Lab.  
Semi Anechoic Chamber No.4  
Date November 27, 2020  
Temperature / Humidity 23 deg. C / 43 % RH  
Engineer Akihiko Maeda  
(Below 1 GHz)  
Mode 1  
Mode 1

Limit : FCC\_Part 15 Subpart B(15.109)\_Class B



No.	Freq. [MHz]	Reading [dBuV]	Ant.Fac [dB/m]	Loss [dB]	Gain [dB]	Result	Limit	Margh	Pola.	Height [cm]	Angle [deg.]	Ant. Type	Comment
						[QP] [dBuV/m]	[QP] [dBuV/m]	[QP] [dB]					
1	32.953	21.00	17.26	7.17	32.20	13.23	40.00	26.77	Hori.	300	2	BA	
2	55.441	21.00	9.14	7.49	32.16	5.47	40.00	34.53	Hori.	300	352	BA	
3	126.287	20.10	13.34	8.21	32.11	9.54	43.50	33.96	Hori.	300	321	BA	
4	314.720	24.20	13.92	9.67	31.98	15.81	46.00	30.19	Hori.	100	352	LA23	
5	315.280	24.50	13.94	9.67	31.98	16.13	46.00	29.87	Hori.	100	352	LA23	
6	630.560	20.10	19.45	11.34	31.99	18.90	46.00	27.10	Hori.	100	234	LA23	
7	945.840	19.30	21.84	12.56	30.65	23.05	46.00	22.95	Hori.	100	348	LA23	
8	32.953	21.00	17.26	7.17	32.20	13.23	40.00	26.77	Vert.	100	178	BA	
9	55.441	24.00	9.14	7.49	32.16	8.47	40.00	31.53	Vert.	100	276	BA	
10	126.287	20.10	13.34	8.21	32.11	9.54	43.50	33.96	Vert.	100	324	BA	
11	314.720	23.90	13.92	9.67	31.98	15.51	46.00	30.49	Vert.	100	14	LA23	
12	315.280	24.30	13.94	9.67	31.98	15.93	46.00	30.07	Vert.	100	14	LA23	
13	630.560	20.10	19.45	11.34	31.99	18.90	46.00	27.10	Vert.	100	78	LA23	
14	945.840	19.20	21.84	12.56	30.65	22.95	46.00	23.05	Vert.	100	187	LA23	

CHART: WITH FACTOR

ANT TYPE: - 30 MHz: LOOP, 30 MHz - 200 MHz: BICONICAL, 200 MHz - 1000 MHz: LOGPERIODIC, 1000 MHz -: HORN

CALCULATION: RESULT = READING + ANT FACTOR + LOSS(CABLE + ATT) - GAIN(AMP)

Except for the above table: adequate margin data below the limits.

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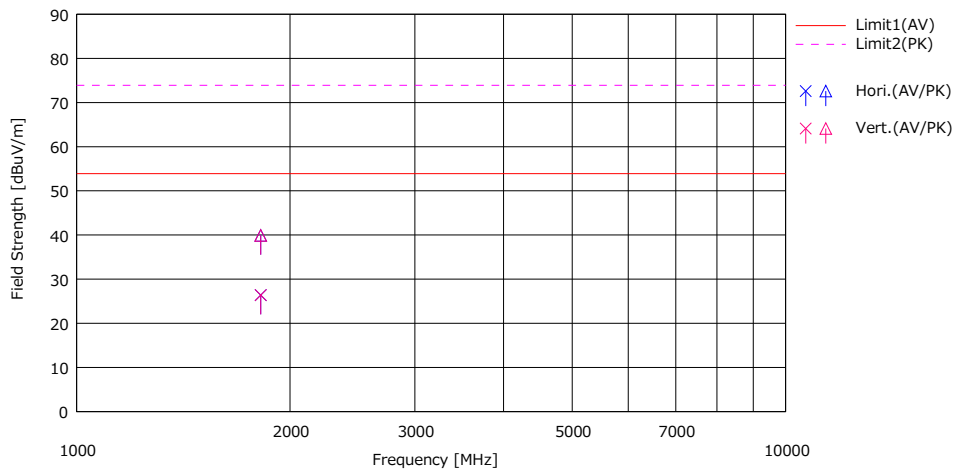
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## Radiated Emission

Report No. 13584430H  
Test place Ise EMC Lab.  
Semi Anechoic Chamber No.4  
Date November 27, 2020  
Temperature / Humidity 23 deg. C / 43 % RH  
Engineer Akihiko Maeda  
(Above 1 GHz)  
Mode Mode 1

Limit : FCC\_Part 15 Subpart B(15.109)\_Class B



No.	Freq. [MHz]	Reading		Ant.Fac. [dB]	Loss [dB]	Gain [dB]	Result		Limit		Margin		Pola. [H/V]	Height [cm]	Angle [deg]	Ant. Type	Comment
		(AV) [dBuV]	(PK) [dBuV]				(AV) [dBuV/m]	(PK) [dBuV/m]	(AV) [dBuV/m]	(PK) [dBuV/m]	(AV) [dB]	(PK) [dB]					
1	1818.576	29.20	42.70	25.32	4.31	32.43	26.40	39.90	53.90	73.90	27.5	34.0	Hori.	100	0	H21	
2	1818.576	29.20	42.70	25.32	4.31	32.43	26.40	39.90	53.90	73.90	27.5	34.0	Vert.	100	0	H21	

CHART: WITH FACTOR

ANT TYPE: - 30 MHz: LOOP, 30 MHz - 200 MHz: BICONICAL, 200 MHz - 1000 MHz: LOGPERIODIC, 1000 MHz -: HORN

CALCULATION: RESULT = READING + ANT FACTOR + LOSS(CABLE + D-factor) - GAIN(AMP)

Except for the above table: adequate margin data below the limits.

\*The VCO (1888.32 MHz) was measured and the level was below Floor Noise.

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## **APPENDIX 2: Test instruments**

### **Test equipment**

Test Item	Local ID	LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Cal Int
RE	MAEC-04	142011	AC4_Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	05/25/2020	24
RE	MOS-15	141562	Thermo-Hygrometer	CUSTOM. Inc	CTH-201	0010	01/07/2020	12
RE	MMM-10	141545	DIGITAL HiTESTER	Hioki	3805	51201148	01/06/2020	12
RE	MJM-29	142230	Measure	KOMELON	KMC-36	-	-	-
RE	COTS-ME MI-02	178648	EMI measurement program	TSJ (Techno Science Japan)	TEPTO-DV	-	-	-
RE	MAEC-04-SVSWR	142017	AC4_Semi Anechoic Chamber(SVSWR)	TDK	Semi Anechoic Chamber 3m	DA-10005	04/04/2019	24
RE	MTR-10	141951	EMI Test Receiver	Rohde & Schwarz	ESR26	101408	03/10/2020	12
RE	MBA-05	141425	Biconical Antenna	Schwarzbeck Mess - Elektronik	VHA9103+BBA9106	VHA 91031302	08/31/2020	12
RE	MLA-23	141267	Logperiodic Antenna (200-1000MHz)	Schwarzbeck Mess - Elektronik	VUSLP9111B	9111B-192	09/02/2020	12
RE	MAT-34	141331	Attenuator(6dB)	TME	UFA-01	-	02/05/2020	12
RE	MCC-50	141397	Coaxial Cable	UL Japan	-	-	11/06/2020	12
RE	MPA-13	141582	Pre Amplifier	SONOMA INSTRUMENT	310	260834	02/10/2020	12
RE	MHA-21	141508	Horn Antenna 1-18GHz	Schwarzbeck Mess - Elektronik	BBHA9120D	557	05/22/2020	12
RE	MCC-246	199563	Microwave Cable	HUBER+SUNER	SF126E/11PC35/11PC35/1000M,5000M	537061/126E / 537072/126E	06/11/2020	12
RE	MPA-12	141581	MicroWave System Amplifier	Keysight Technologies Inc	83017A	00650	10/19/2020	12

\*Hyphens for Last Calibration Date and Cal Int (month) are instruments that Calibration is not required (e.g. software), or instruments checked in advance before use.

The expiration date of the calibration is the end of the expired month.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

Test item:

RE: Radiated emission

**UL Japan, Inc.**

**Ise EMC Lab.**

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